## Application/Control No. Applicant(s)/Patent Under Reexamination 10/074,649 TRUTNAU ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Jeffrey R. Snay 1743 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-3,726,297 04-1973 Heimann et al. Α 137/1 В US-5,010,776 04-1991 Lucero et al. 73/863.23 С US-5,783,756 07-1998 Xiong et al. 73/863.23 D US-2,667,075 01-1954 BLUM ALVIN S; et. al. 73/864.63 Ε US-2001/0041152 11-2001 Zigler et al. 422/100 US-4,152,591 05-1979 Averitt et al. 378/47 G US-4,667,100 05-1987 Lagna, William M. 250/282 Н US-USυŠ J US-Κ L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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